

MEASUREMENT REPORT

FCC Part 30 5G mmWave

Applicant Name:

Samsung Electronics Co., Ltd.
129, Samsung-ro,
Yeongtong-gu, Suwon-si
Gyeonggi-do, 16677, Korea

Date of Testing:

03/09 - 04/10/2020

Test Site/Location:

PCTEST Lab. Columbia, MD, USA

Test Report Serial No.:

1M2003120043-06.A3L

FCC ID:

A3LSMG988U

APPLICANT:

Samsung Electronics Co., Ltd.

Application Type:

Class II Permissive Change

Model:

SM-G988U

Additional Model(s):

SM-G988U1, SM-G988W

EUT Type:

Portable Handset

FCC Classification:

Part 30 Mobile Transmitter (5GM)

FCC Rule Part(s):

30

Test Procedure(s):

ANSI C63.26-2015, KDB 971168 D01 v03r01, KDB 842590 D01 v01

This equipment has been shown to be capable of compliance with the applicable technical standards as indicated in the measurement report and was tested in accordance with the measurement procedures specified in §2.947. Test results reported herein relate only to the item(s) tested.

I attest to the accuracy of data. All measurements reported herein were performed by me or were made under my supervision and are correct to the best of my knowledge and belief. I assume full responsibility for the completeness of these measurements and vouch for the qualifications of all persons taking them.



Randy Ortanez
President

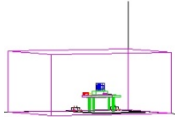


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T A B L E O F C O N T E N T S

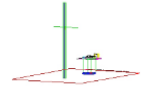
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MEASUREMENT REPORT

FCC Part 30



Antenna	Mode	Bandwidth (MHz)	CCs Active	Band	FCC Rule Part	Tx Frequency (MHz)	EIRP		Emission Designator	Modulation	Modulation
							Max. Power (W)	Max. Power (dBm)			
Ant2	SISO	50	1	n261	30	27500 - 28350	0.214	23.30	48M3G7D	QPSK	BPSK
Ant2	SISO	50	2	n261	30	27500 - 28350			95M0G7D	QPSK	BPSK
Ant2	SISO	100	1	n261	30	27500 - 28350			90M6G7D	QPSK	BPSK
Ant2	SISO	100	2	n261	30	27500 - 28350			190MG7D	QPSK	BPSK

EUT Overview (J Patch / Ant2 - Band n261)

Antenna	Mode	Bandwidth (MHz)	CCs Active	Band	FCC Rule Part	Tx Frequency (MHz)	EIRP		Emission Designator	Modulation	Modulation
							Max. Power (W)	Max. Power (dBm)			
Ant2	SISO	50	1	n260	30	37000 - 40000			45M3G7D	QPSK	BPSK
Ant2	SISO	50	2	n260	30	37000 - 40000			94M5G7D	QPSK	BPSK
Ant2	SISO	100	1	n260	30	37000 - 40000	0.324	25.11	91M1G7D	QPSK	BPSK
Ant2	SISO	100	2	n260	30	37000 - 40000			189MG7D	QPSK	BPSK

EUT Overview (J Patch / Ant2 - Band n260)

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1.0 INTRODUCTION

1.1 Scope

Measurement and determination of electromagnetic emissions (EMC) of radio frequency devices including intentional and/or unintentional radiators for compliance with the technical rules and regulations of the Federal Communications Commission and the Innovation, Science and Economic Development Canada.

1.2 PCTEST Test Location

These measurement tests were conducted at the PCTEST Engineering Laboratory, Inc. facility located at 7185 Oakland Mills Road, Columbia, MD 21046. The measurement facility is compliant with the test site requirements specified in ANSI C63.4-2014.

1.3 Test Facility / Accreditations

Measurements were performed at PCTEST Engineering Lab located in Columbia, MD 21046, U.S.A.

- PCTEST is an ISO 17025-2005 accredited test facility under the American Association for Laboratory Accreditation (A2LA) with Certificate number 2041.01 for Specific Absorption Rate (SAR), Hearing Aid Compatibility (HAC) testing, where applicable, and Electromagnetic Compatibility (EMC) testing for FCC and Innovation, Science, and Economic Development Canada rules.
- PCTEST TCB is a Telecommunication Certification Body (TCB) accredited to ISO/IEC 17065-2012 by A2LA (Certificate number 2041.03) in all scopes of FCC Rules and ISSED Standards (RSS).
- PCTEST facility is a registered (2451B) test laboratory with the site description on file with ISSED.

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2.0 PRODUCT INFORMATION

2.1 Equipment Description

The Equipment Under Test (EUT) is the **Samsung Portable Handset FCC ID: A3LSMG988U**. The test data contained in this report pertains only to the emissions due to the EUT's 5G mmWave function.

The EUT has 2 array antenna configurations. Type1: 4 patches and 4 dipoles, placed on the rear side (denoted as J Patch and J Dipole). Type 2: 4 patches only, placed on the left and right side (denoted as K patch and L Patch). Each of the patch antennas is comprised of two separate antenna feeds - one for horizontal and one for vertical polarization. Only one array antenna can be active at a time. Dipole antenna does not radiate when patch antenna radiates.

The EUT supports up to 8CC for DL, and 4CC for UL. For each CC, the EUT supports both 50MHz bandwidth and 100MHz bandwidth. For modulation, the EUT supports a subcarrier spacing (SCS) of 120kHz with two transmission schemes, CP-OFDM and DFT-s-OFDM, with BPSK, QPSK, 16-QAM, and 64-QAM modulations. Different Beam IDs are supported, each corresponding to a different position in space for each antenna. During testing, FTM (Factory Test Mode) was used to operate the transmitter. MIMO operation was achieved by enabling two Beam IDs at the same time: one is from the list of H Beam IDs and other is from the list of V Beam IDs.

Antenna	Name
Ant1	J Dipole
Ant2	J Patch
Ant3	K Patch
Ant4	L Patch

Test Device Serial No.: 0860M, 0842M

2.2 Device Capabilities

This device contains the following capabilities:

850/1900 CDMA/EvDO Rev0/A, 1x Advanced (BC0, BC1, BC10), 850/1900 GSM/GPRS/EDGE, 850/1700/1900 WCDMA/HSPA, Multi-band LTE, 5G NR (n71, n5, n66, n2, n41, n260, n261), 802.11b/g/n/ax WLAN, 802.11a/n/ac/ax UNII, Bluetooth (1x, EDR, LE), NFC, ANT+, Wireless Power Transfer

2.3 Test Configuration

The EUT was tested per the guidance of KDB 842590 D01 v01 and ANSI C63.26-2015. See Section 7.0 of this test report for a description of the radiated tests.

EIRP Simulation data for all Beam IDs was used to determine the worst case Beam ID for SISO operation and Beam ID pair for MIMO operation. These Beam ID's were used for final measurements.

All testing was performed using FTM (Factory Test Mode) software at continuous Tx operation. When implemented out in the field, the EUT will operate with a maximum uplink configuration (i.e., a maximum uplink duty cycle of 100%).

2.4 EMI Suppression Device(s)/Modifications

No EMI suppression device(s) were added and no modifications were made during testing.

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3.0 DESCRIPTION OF TESTS

3.1 Measurement Procedure

The measurement procedures described in the document titled "American National Standard for Compliance Testing of Transmitters Used in Licensed Radio Services" (ANSI C63.26-2015) and the guidance provided in KDB 842590 D01 v01 were used in the measurement of the EUT.

3.2 Radiated Power and Radiated Spurious Emissions

§30.202, §30.203

The radiated test facilities consisted of an indoor 3 meter semi-anechoic chamber used for final measurements and exploratory measurements, when necessary for radiated emissions measurements in the spurious domain. The measurement area is contained within the semi-anechoic chamber which is shielded from any ambient interference. The test site inside the chamber is a 6m x 5.2m elliptical, obstruction-free area in accordance with Figure 5.7 of Clause 5 in ANSI C63.4-2014. Absorbers are arranged on the floor between the turn table and the antenna mast in such a way so as to maximize the reduction of reflections for measurements above 1GHz. For measurements below 1GHz, the absorbers are removed. A raised turntable is used for radiated measurement. The turn table is a continuously rotatable, remote-controlled, metallic turntable and 2 meters (6.56 ft.) in diameter. The turn table is flush with the raised floor of the chamber in order to maintain its function as a ground plane. An 80cm tall test table made of Styrodur is placed on top of the turn table. A Styrodur pedestal is placed on top of the test table to bring the total table height to 1.5m for measurements above 1GHz.

Radiated power (EIRP) measurements were performed in a full anechoic chamber (FAC) conforming to the site validation requirements of CISPR 16-1-4. A positioner was used to manipulate the EUT through several positions in space by rotating about the roll axis as shown in the figure below. The positioner was mounted on top of a turntable bringing the total EUT height to 1.5m.

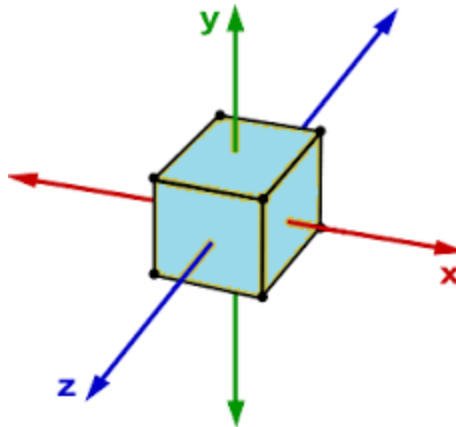


Figure 3-1. Rotation of the EUT through horizontal and vertical axis

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The equipment under test was transmitting while connected to its integral antenna and is placed on a turntable. The measurement antenna is in the far field of the EUT per formula $2D^2/\lambda$ where D is the larger between the dimension of the measurement antenna and the transmitting antenna of the EUT. In this case, D is the largest dimension of the measurement antenna. The EUT is manipulated through all orthogonal planes representative of its typical use to achieve the highest reading on the receive spectrum analyzer.

Frequency Range (GHz)	Wavelength(cm)	Far Field Distance (m)	Measurement Distance (m)
18-40	0.749	0.54	1.00
40-60	0.500	1.39	1.50
60-90	0.333	0.91	1.00
90-140	0.214	0.58	1.00
140-200	0.150	0.39	1.00

Table 3-1. Far-Field Distance & Measurement Distance per Frequency Range

Radiated power levels are investigated while the receive antenna was rotated through all angles to determine the worst case polarization/positioning. It was determined that H=0 degree and V=90 degree are the worst case positions when the EUT was transmitting horizontally and vertically polarized beams, respectively.

The maximized power level is recorded using the spectrum analyzer "Channel Power" function with the integration bandwidth set to the emissions' occupied bandwidth. The EIRP is calculated from the raw power level measured with the spectrum analyzer using the formulas shown below.

Effective Isotropic Radiated Power Sample Calculation

The measured e.i.r.p is converted to E-field in V/m. Then, the distance correction is applied before converting back to calculated e.i.r.p, as explained in KDB 971168 D01.

$$\begin{aligned}
 \text{Field Strength [dB}\mu\text{V/m]} &= \text{Measured Value [dBm]} + \text{AFCL [dB/m]} + 107 \\
 &= -32.74 \text{ dBm} + (40.7 \text{ dB/m} + 8.78 \text{ dB}) + 107 = 123.74 \text{ dB}\mu\text{V/m} \\
 &= 10^{(123.74/20)/1000000} = 1.54 \text{ V/m} \\
 \text{e.i.r.p. [dBm]} &= 10 * \log((\text{E-Field} * D_m)^2/30) + 30 \text{ dB} \\
 &= 10 * \log((1.54 \text{ V/m} * 1.00 \text{ m})^2/30) + 30 \text{ dB} \\
 &= 18.98 \text{ dBm e.i.r.p.}
 \end{aligned}$$

Sample MIMO e.i.r.p. Calculation:

The e.i.r.p of the H Beam and V Beam were first measured individually. The measured values were then summed in linear power units then converted back to dBm per the guidance of KDB 662911 D01.

$$\begin{aligned}
 \text{Conversion to linear value} &= 10^{(\text{e.i.r.p}/10)} = 10^{(17.45/10)} = 55.59 \text{ mW} \\
 \text{MIMO e.i.r.p.} &= \text{e.i.r.p.H} + \text{e.i.r.p.V} \\
 &= 55.59 \text{ mW} + 20.04 \text{ mW} \\
 &= 10 * \log(75.63 \text{ mW}) \\
 &= 18.79 \text{ dBm}
 \end{aligned}$$

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4.0 MEASUREMENT UNCERTAINTY

The measurement uncertainties shown below were calculated in accordance with the requirements of ANSI C63.4-2014. All measurement uncertainty values are shown with a coverage factor of $k = 2$ to indicate a 95% level of confidence. The measurement uncertainty shown below meets or exceeds the U_{CISPR} measurement uncertainty values specified in CISPR 16-4-2 and, thus, can be compared directly to specified limits to determine compliance.

Contribution	Expanded Uncertainty ($\pm$ dB)
Conducted Bench Top Measurements	1.13
Radiated Disturbance (<1GHz)	4.98
Radiated Disturbance (>1GHz)	5.07
Radiated Disturbance (>18GHz)	5.09

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5.0 TEST EQUIPMENT CALIBRATION DATA

Test Equipment Calibration is traceable to an accredited ISO/IEC 17025 calibration facility. Measurements antennas used during testing were calibrated in accordance to the requirements of ANSI C63.5-2017.

Manufacturer	Model	Description	Cal Date	Cal Interval	Cal Due	Serial Number
Agilent	N9030A	PXA Signal Analyzer (44GHz)	6/12/2019	Annual	6/12/2020	MY52350166
Agilent	N9030A	50GHz PXA Signal Analyzer	11/22/2019	Annual	11/22/2020	US51350301
COM-Power	AL-130R	Active Loop Antenna	8/22/2019	Annual	8/22/2020	121085
Com-Power	PAM-103	Pre-Amplifier (1-1000MHz)	5/10/2019	Annual	5/10/2020	441112
Emco	3115	Horn Antenna (1-18GHz)	3/28/2018	Biennial	3/28/2020	9704-5182
Espec	ESX-2CA	Environmental Chamber	6/13/2019	Annual	6/13/2020	17620
ETS-Lindgren	3116C	DRG Horn Antenna	3/11/2019	Annual	3/11/2020	218893
Keysight Technologies	N9030A	3Hz-44GHz PXA Signal Analyzer	5/2/2019	Annual	5/2/2020	MY49430494
OML Inc.	M05RH	WR-05 Horn antenna, 24 dBi, 140 to 200GHz	10/31/2019	Annual	10/31/2020	18073001
OML Inc.	M08RH	WR-08 Horn Antenna, 24dBi, 90 to 140 GHz	7/30/2018	Biennial	7/30/2020	18073001
OML Inc.	M12RH	WR-12 Horn Antenna, 24dBi, 60 to 90 GHz	10/31/2019	Annual	10/31/2020	18073001
OML Inc.	M19RH	WR-19 Horn Antenna, 24dBi, 40 to 60 GHz	10/31/2019	Annual	10/31/2020	18073001
Rohde & Schwarz	180-442-KF	Horn (Small)	8/21/2018	Biennial	8/21/2020	U157403-01
Rohde & Schwarz	ESU26	EMI Test Receiver (26.5GHz)	6/5/2019	Annual	6/5/2020	100342
Rohde & Schwarz	ESW44	EMI Test Receiver 2Hz to 44 GHz	10/16/2019	Annual	10/16/2020	101716
Rohde & Schwarz	FSW67	Signal / Spectrum Analyzer	5/6/2019	Annual	5/6/2020	103200
Rohde & Schwarz	SFUNIT-Rx	Shielded Filter Unit	7/8/2019	Annual	7/8/2020	102133
Sunol	JB5	Bi-Log Antenna (30M - 5GHz)	4/19/2018	Biennial	4/19/2020	A051107
Virginia Diodes Inc	SAX252	SAX Module (60 - 90GHz)	9/30/2019	Annual	9/30/2020	SAX252
Virginia Diodes Inc	SAX253	SAX Module (90 - 140GHz)	9/30/2019	Annual	9/30/2020	SAX253
Virginia Diodes Inc	SAX254	SAX Module (140 - 220GHz)	9/30/2019	Annual	9/30/2020	SAX254
Virginia Diodes Inc	SAX411	SAX Module (40 - 60GHz)	10/2/2019	Annual	10/2/2020	SAX411

Table 5-1. Test Equipment

Notes:

- For equipment listed above that has a calibration date or calibration due date that falls within the test date range, care was taken to ensure that this equipment was used after the calibration date and before the calibration due date.

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6.0 SAMPLE CALCULATIONS

Emission Designator

BPSK Modulation

Emission Designator = 800MG7D

BW = 800 MHz

G = Phase Modulation

7 = Quantized/Digital Info

D = Data transmission, telemetry, telecommand

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7.0 TEST RESULTS

7.1 Summary

Company Name: Samsung Electronics Co., Ltd.
 FCC ID: A3LSMG988U
 FCC Classification: Part 30 Mobile Transmitter (5GM)
 Mode(s): TDD

FCC Part Section(s)	Test Description	Test Limit	Test Condition	Test Result	Reference
2.1049	Occupied Bandwidth	N/A	RADIATED	PASS	Section 7.2
2.1046, 30.202	Equivalent Isotropic Radiated Power	43dBm		PASS	Section 7.3
2.1051, 30.203	Spurious Emissions	-13dBm/MHz for all out-of-band emissions		PASS	Section 7.4
2.1051, 30.203	Out-of-Band Emissions at the Band Edge	-13dBm/MHz for all out-of-band emissions, -5dBm/MHz from the band edge up to 10% of the channel BW		PASS	Section 7.5

Table 7-1. Summary of Radiated Test Results

Notes:

- 1) All modes of operation and modulations were investigated. The test results shown in the following sections represent the worst case emissions.
- 2) Per 2.1057(a)(2), spurious emissions were investigated up to 100GHz for n261 and up to 200GHz for n260.
- 3) All radiated emission measurements at the band edge are converted to an equivalent conductive power by subtracting the known antenna gain from the EIRP measured at each frequency of interest. These emissions are compared to the 30.203 spurious emission limits as conductive power levels.
- 4) The radiated RF output power and all out-of-band emissions in the spurious domain are evaluated to the EIRP limits.
- 5) "CC" refers to "Component Carriers".
- 6) Beam IDs were chosen based on which Beam ID produces the highest EIRP during EIRP simulation.
- 7) All testing was performed using FTM (Factory Test Mode) software at continuous Tx operation (100% duty cycle).
- 8) The CP-OFDM and DFT-s-OFDM BPSK, QPSK transmission schemes were investigated fully for each test type and only the worst case data is included.

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7.2 Occupied Bandwidth

\$2.1049

Test Overview

The occupied bandwidth, that is the frequency bandwidth such that, below its lower and above its upper frequency limits, the mean powers radiated are each equal to 0.5 percent of the total mean power radiated by a given emission shall be measured. All modes of operation were investigated and the worst case configuration results are reported in this section.

Test Procedure Used

ANSI C63.26-2015 Section 5.4.3
KDB 842590 D01 v01 Section 4.3

Test Settings

1. The signal analyzer's automatic bandwidth measurement capability was used to perform the 99% occupied bandwidth. The bandwidth measurement was not influenced by any intermediate power nulls in the fundamental emission.
2. RBW = 1 – 5% of the expected OBW
3. VBW $\geq 3 \times$ RBW
4. Detector = Peak
5. Trace mode = max hold
6. Sweep = auto couple
7. The trace was allowed to stabilize
8. If necessary, steps 2 – 7 were repeated after changing the RBW such that it would be within 1 – 5% of the 99% occupied bandwidth observed in Step 7

Test Notes

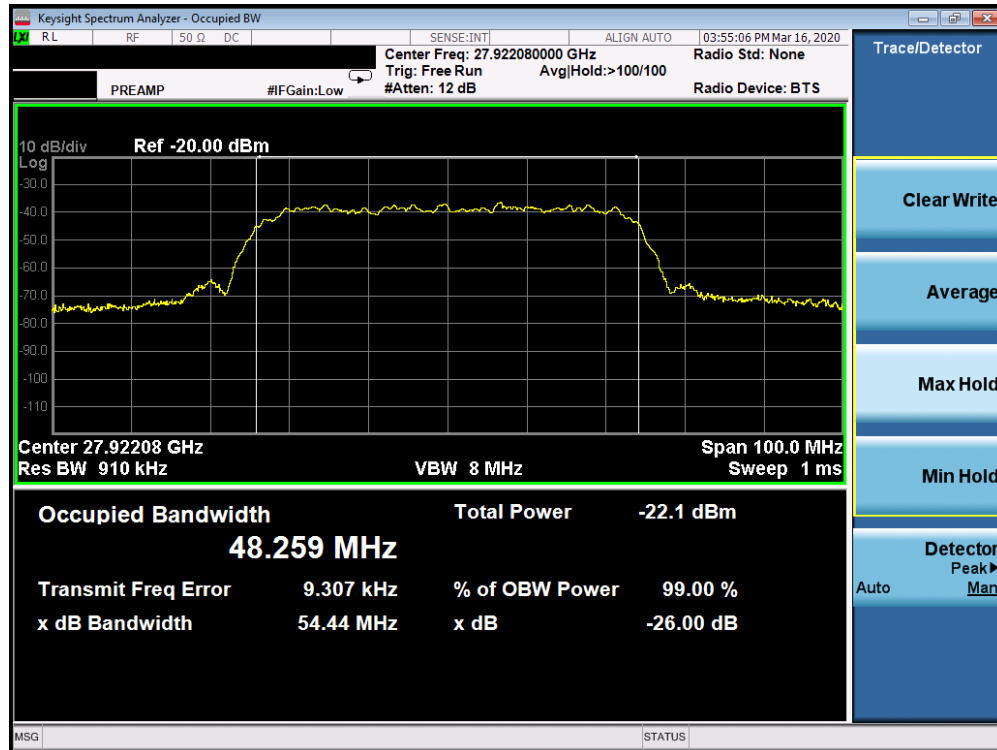
The EUT supports CP (QPSK) and DFT-s (QPSK), DFT-s (BPSK). All modulations were investigated in detail. Data for the worst case has been included in the report.

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Band n261

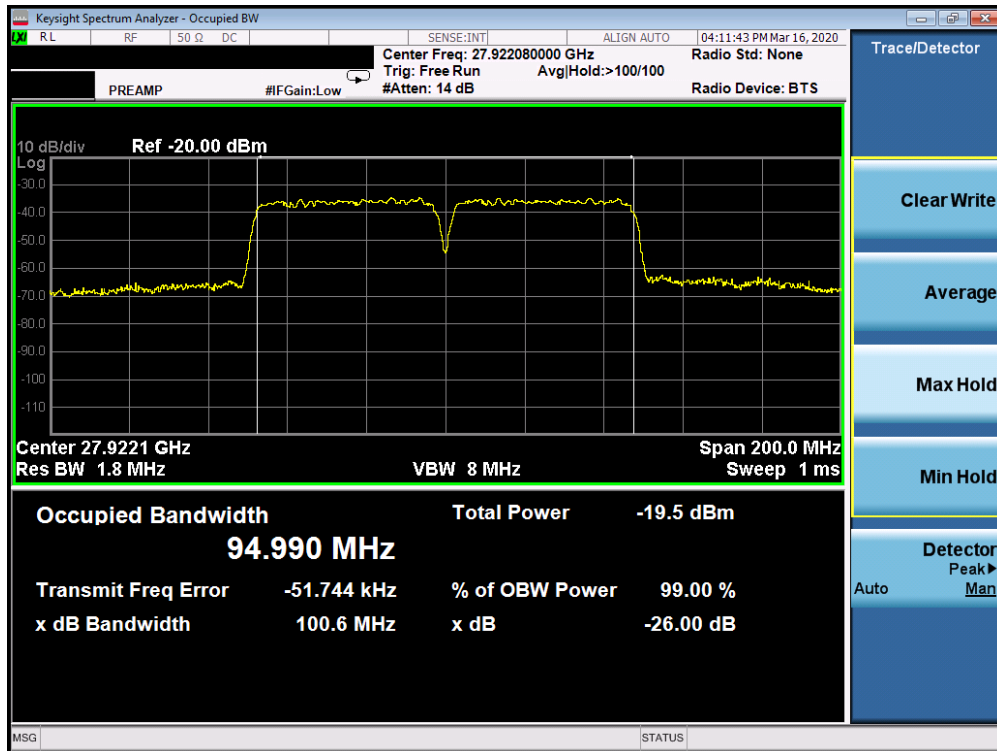
Channel	Bandwidth	CCs Active	Modulation	OBW [MHz]
Mid	50	1	BPSK	48.53
		2	BPSK	94.99
	100	1	BPSK	90.60
		2	BPSK	190.05

Table 7-2. Summary of Ant2 Occupied Bandwidths (n261)

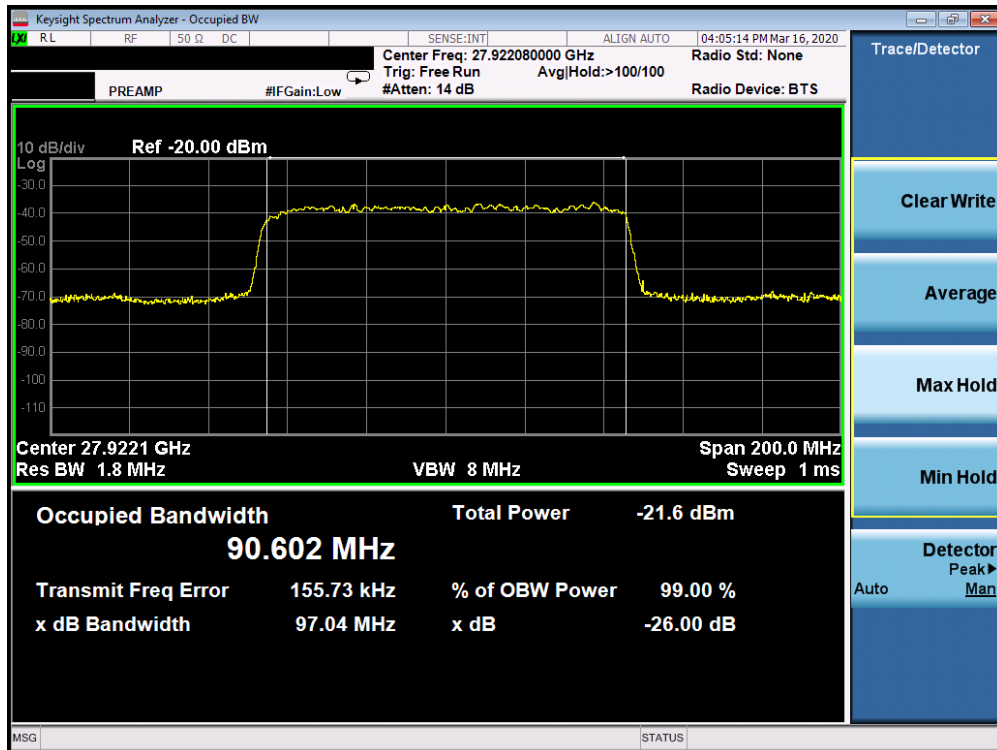


Plot 7-1. Ant2 Occupied Bandwidth Plot (50MHz-1CC – DFT-s-OFDM-BPSK – Mid Channel)

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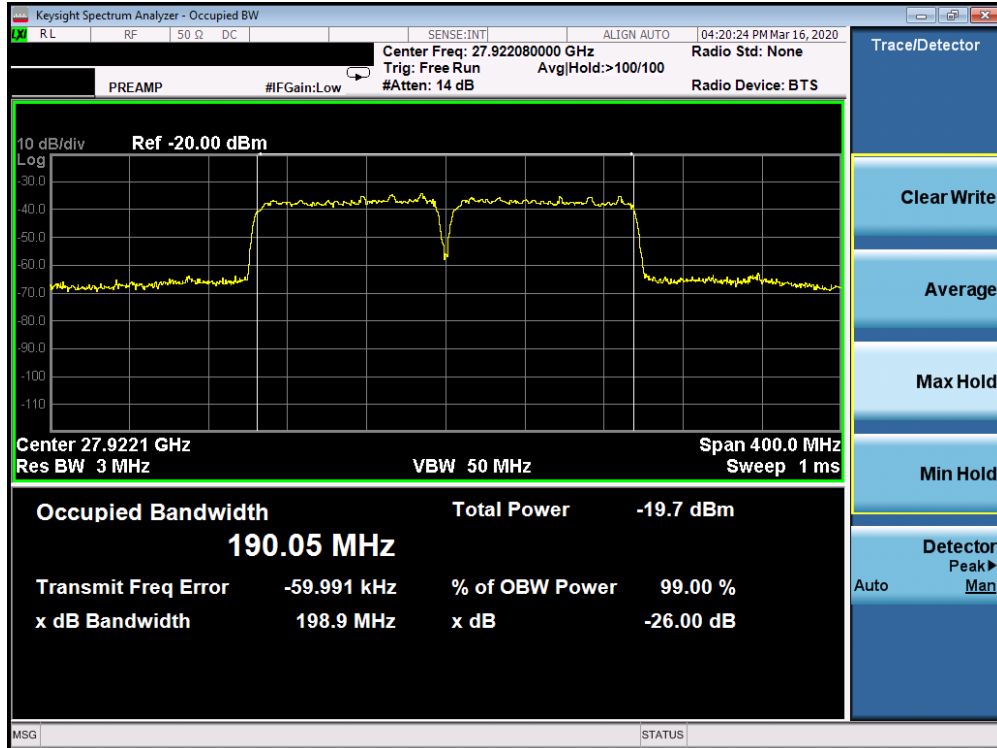


Plot 7-2. Ant2 Occupied Bandwidth Plot (50MHz-2CC – DFT-s-OFDM-BPSK – Mid Channel)



Plot 7-3. Ant2 Occupied Bandwidth Plot (100MHz-1CC – DFT-s-OFDM-BPSK – Mid Channel)

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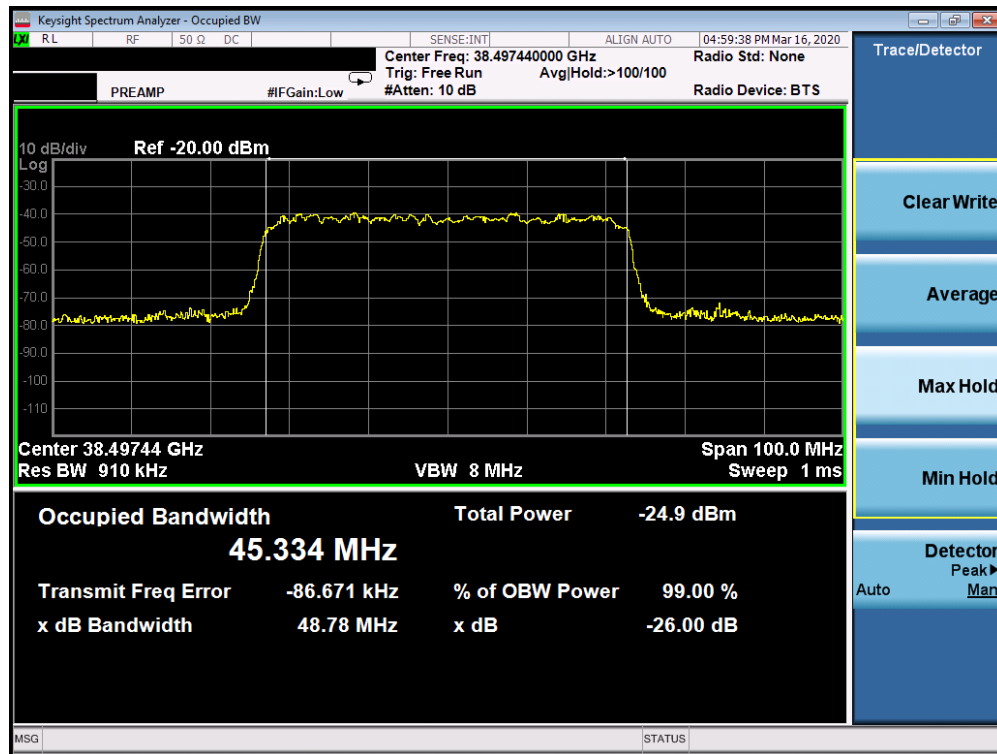
Plot 7-4. Ant2 Occupied Bandwidth Plot (100MHz-2CC – DFT-s-OFDM-BPSK – Mid Channel)

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Band n260

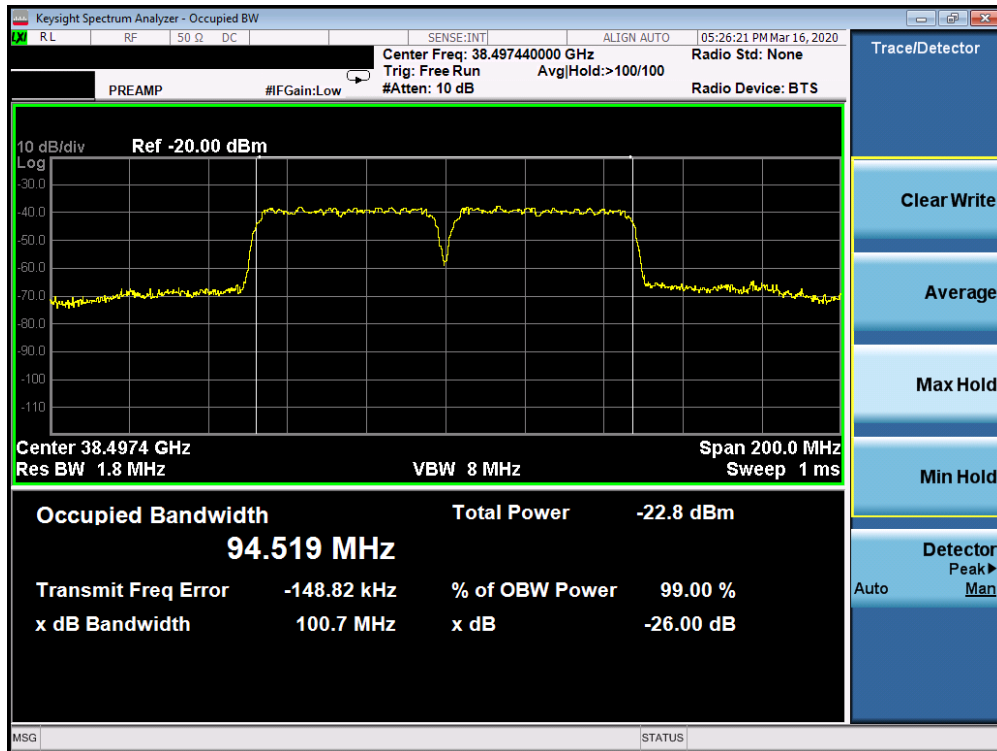
Channel	Bandwidth	CCs Active	Modulation	OBW [MHz]
Mid	50	1	BPSK	45.33
		2	BPSK	94.52
	100	1	BPSK	91.08
		2	BPSK	189.40

Table 7-3. Summary of Ant2 Occupied Bandwidths (n260)

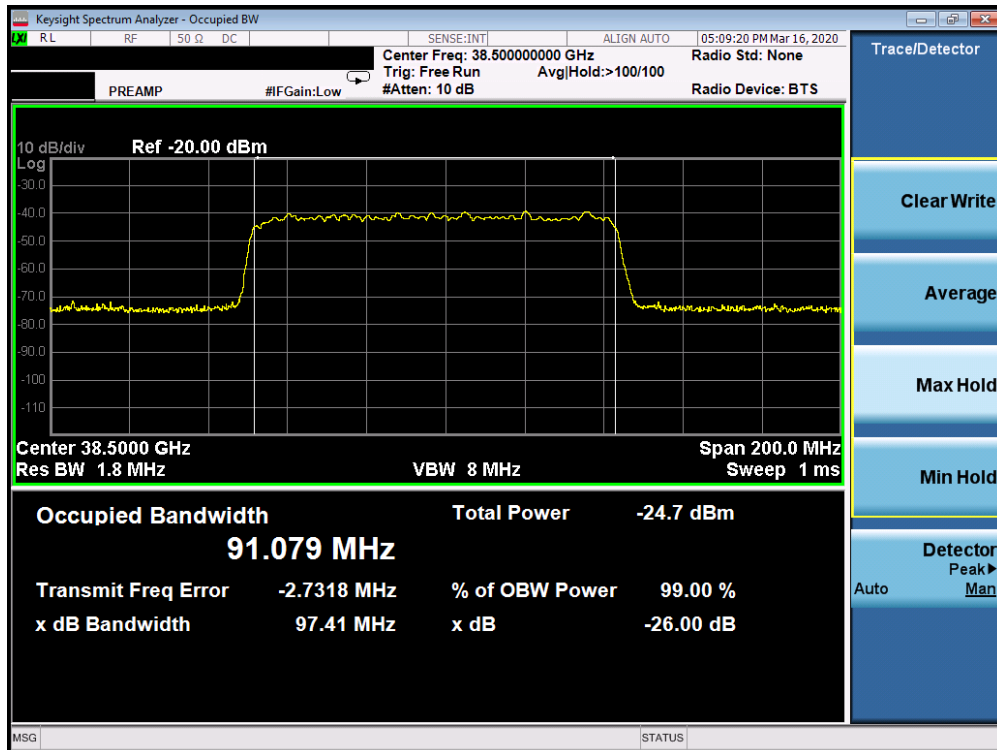


Plot 7-5. Ant2 Occupied Bandwidth Plot (50MHz-1CC – DFT-s-OFDM-BPSK – Mid Channel)

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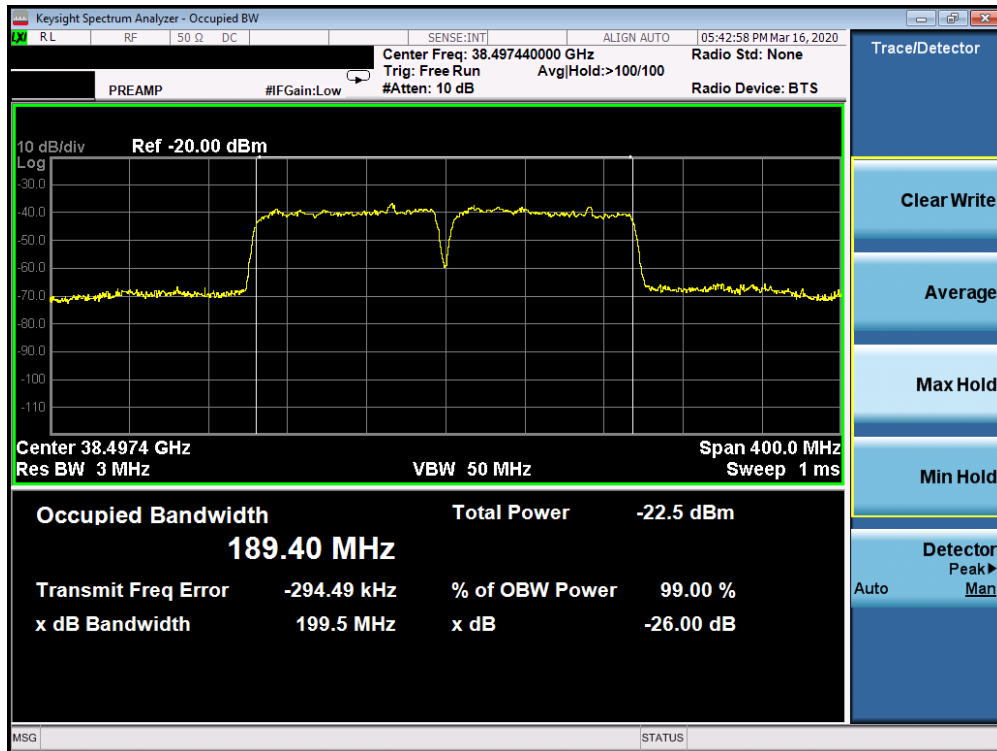


Plot 7-6. Ant2 Occupied Bandwidth Plot (50MHz-2CC – DFT-s-OFDM-BPSK – Mid Channel)



Plot 7-7. Ant2 Occupied Bandwidth Plot (100MHz-1CC – DFT-s-OFDM-BPSK – Mid Channel)

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Plot 7-8. Ant2 Occupied Bandwidth Plot (100MHz-2CC – DFT-s-OFDM-BPSK – Mid Channel)

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7.3 Equivalent Isotropic Radiated Power

\$2.1046, \$30.202

Test Overview

Equivalent Isotropic Radiated Power (EIRP) measurements are performed using broadband horn antennas. All measurements are performed as RMS average measurements while the EUT is operating at its maximum duty cycle, at maximum power, and at the appropriate frequencies.

The average power of the sum of all antenna elements is limited to a maximum EIRP of +43 dBm.

Test Procedures Used

ANSI C63.26-2015 Section 5.2.4.4.1
KDB 842590 D01 v01 Section 4.2

Test Settings

1. Radiated power measurements are performed using the signal analyzer's "channel power" measurement capability for signals with continuous operation.
2. RBW = 1 – 5% of the expected OBW, not to exceed 1MHz
3. VBW $\geq 3 \times$ RBW
4. Span = 2x to 3x the OBW
5. No. of sweep points $\geq 2 \times$ span / RBW
6. Detector = RMS
7. The integration bandwidth was roughly set equal to the measured OBW of the signal for signals with continuous operation.
8. Trace mode = trace averaging (RMS) over 100 sweeps
9. The trace was allowed to stabilize

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Test Notes

- 1) The EUT was tested in three orthogonal planes and in all possible test configurations and positioning. The worst case emissions are reported with the EUT positioning, modulations, RB sizes and offsets, and channel bandwidth configurations shown in the tables below.
- 2) Elements within the same antenna array are correlated to produce beamforming array gain. Antenna arrays cannot be correlated with another antenna array. During testing, only one antenna array was active.
- 3) EIRP measurements were taken at 1m test distance.
- 4) The average EIRP reported below is calculated per section 5.2.7 of ANSI C63.26-2015 which states: EIRP (dBm) = E (dBμV/m) + 20log(D) – 104.8; where D is the measurement distance (in the far field region) in m. The field strength E is calculated E (dBμV/m) = Spectrum Analyzer Channel Power Level (dBm) + Antenna Factor (dB/m) + Cable Loss (dB) + 107.
- 5) Radiated power levels are investigated while the receive antenna was rotated through all angles to determine the worst case polarization/positioning. It was determined that H=0 degree and V=90 degree are the worst case positions when the EUT was transmitting horizontally and vertically polarized beams, respectively.
- 6) The EIRP was measured on all antennae and we are reporting the worst-case SISO configuration for the worst case bandwidth for both the FR2 Bands.

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Band n261 Beam ID Configurations

Mode	Beam Polarization	Beam ID
SISO	H	168
	V	42

Table 7-4. Ant2 Worst Case Beam ID

Band n261

CCs active	Mode	Frequency [MHz]	Channel	Beam Pol	Modulation	Ant. Pol. [H/V]	Turntable Azimuth [degrees]	Positioner Azimuth [degrees]	RB Size/Offset	EIRP [dBm]
1	SISO	27534.84	Low	H	BPSK	H	287	69	1/16	22.45
		27534.84	Low	V	BPSK	V	101	246	1/16	23.30
		27922.08	Mid	H	BPSK	V	292	69	1/16	21.78
		27922.08	Mid	V	BPSK	V	102	238	1/16	22.56
		28319.52	High	H	BPSK	V	287	74	1/16	22.17
		28319.52	High	V	BPSK	V	79	246	1/16	22.12

Table 7-5. Ant2 EIRP Data (Band n261 - 50MHz-1CC)

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Band n260 Beam ID Configurations

Mode	Beam Polarization	Beam ID
SISO	H	155
	V	40

Table 7-6. Ant2 Worst Case Beam ID

Band n260

CCs active	Mode	Frequency [MHz]	Channel	Beam Pol	Modulation	Ant. Pol. [H/V]	Turntable Azimuth [degrees]	Positioner Azimuth [degrees]	RB Size/Offset	EIRP [dBm]
1	SISO	37027.32	Low	H	BPSK	H	103	238	1/32	20.08
		37027.32	Low	V	BPSK	V	81	127	1/32	22.64
		38497.44	Mid	H	BPSK	H	84	253	1/32	19.76
		38497.44	Mid	V	BPSK	V	82	129	1/32	21.89
		39966.24	High	H	BPSK	H	142	271	1/32	21.11
		39966.24	High	V	BPSK	V	86	132	1/32	25.11

Table 7-7. Ant2 EIRP Data (Band n260 - 100MHz-1CC)

FCC ID: A3LSMG988U		MEASUREMENT REPORT (CLASS II PERMISSIVE CHANGE)			Approved by: Quality Manager
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7.4 Radiated Spurious and Harmonic Emissions

§2.1051, §30.203

Test Overview

The spectrum is scanned from 30MHz to 100GHz for n261 and from 30MHz to 200GHz for n260. All out of band emissions are measured in a radiated test setup while the EUT is operating at its maximum duty cycle, at maximum power, and at the appropriate frequencies. All modulations were investigated to determine the worst case configuration. All modes of operation were investigated and the worst case configuration results are reported in this section.

The conductive power or total radiated power of any emissions outside a licensee's frequency block shall be -13dBm/1MHz.

Test Procedure Used

ANSI C63.26-2015 Section 5.7.4
KDB 842590 D01 v01 Section 4.4.2 and Section 4.4.3

Test Settings

1. Start frequency was set to 30MHz and stop frequency was set to 100 GHz for n261 and 200GHz for n260. Several plots are used to show investigations in this entire span.
2. Detector = RMS
3. Trace mode = trace average
4. Sweep time = auto couple
5. Number of sweep points $\geq 2 \times \text{Span/RBW}$
6. The trace was allowed to stabilize
7. RBW = 1MHz, VBW = 3MHz

Test Notes

- 1) The EUT was tested in three orthogonal planes and in all possible test configurations and positioning. The worst case emissions are reported with the EUT positioning, modulations, RB sizes and offsets, and channel bandwidth configurations shown in the tables below.
- 2) All radiated spurious emissions were measured as EIRP to compare with the §30.203 TRP limits.
- 3) Elements within the same antenna array are correlated to produce beamforming array gain. Antenna arrays cannot be correlated with another antenna array. During testing, only one antenna array was active.
- 4) The plots from 1-200GHz show corrected average EIRP levels. Plots below 1GHz are corrected field strength levels. The average EIRP reported below is calculated per section 5.2.7 of ANSI C63.26-2015 which states: $\text{EIRP (dBm)} = E (\text{dB}\mu\text{V/m}) + 20\log(D) - 104.8$; where D is the measurement distance (in the far field region) in m. The field strength E is calculated $E (\text{dB}\mu\text{V/m}) = \text{Spectrum Analyzer Level (dBm)} + \text{Antenna Factor (dB/m)} + \text{Cable Loss (dB)} + \text{Harmonic Mixer Conversion Loss (dB)} + 107$. All appropriate Antenna Factor and Cable Loss have been applied in the spectrum analyzer for each measurement. For measurements > 40GHz, Harmonic Mixer Conversion Loss was also applied to the spectrum analyzer.
- 5) Emissions below 18GHz were measured at a 3 meter test distance, while emissions above 18GHz were measured at the appropriate far field distance. The far field of the mmWave signal is based on formula: $R > 2D^2/\text{wavelength}$, where D is the larger between the dimension of the measurement antenna and the transmitting antenna of the EUT. In this case, D is the largest dimension of the measurement antenna.

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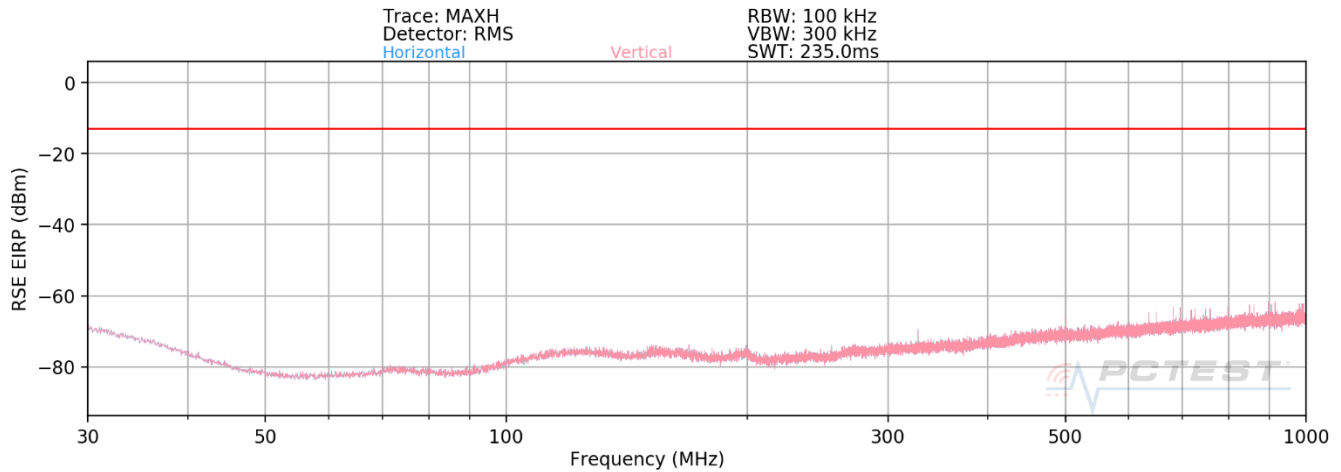
Frequency Range (GHz)	Wavelength(cm)	Far Field Distance (m)	Measurement Distance (m)
18-40	0.749	0.54	1.00
40-60	0.500	1.39	1.50
60-90	0.333	0.91	1.00
90-140	0.214	0.58	1.00
140-200	0.150	0.39	1.00

Table 7-8. Far-Field Distance & Measurement Distance per Frequency Range

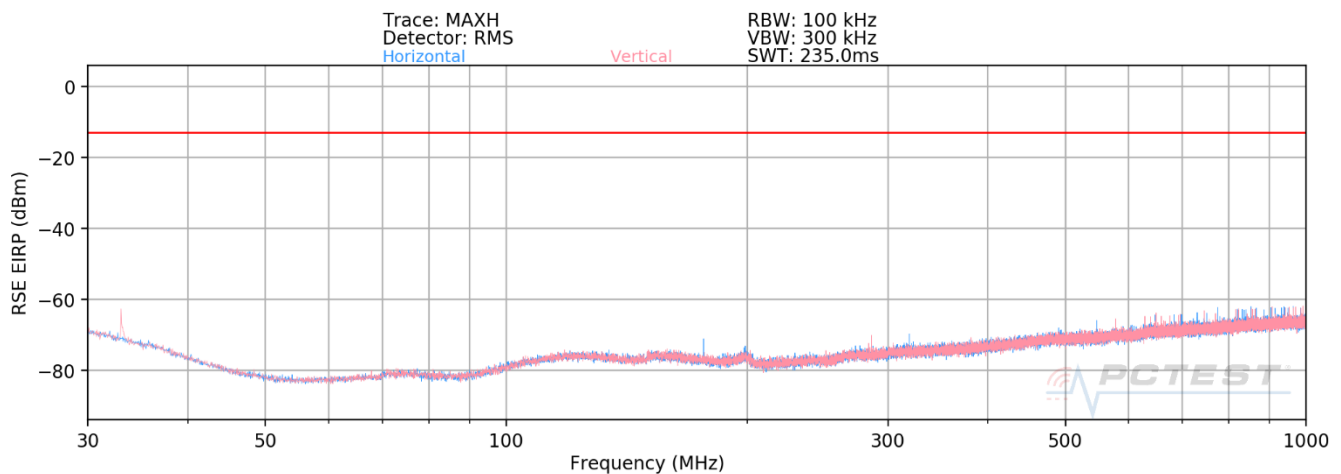
- 6) All emissions from 30MHz - 60GHz were measured using a spectrum analyzer with an internal preamplifier. Emissions >60GHz were measured using a harmonic mixer with the spectrum analyzer.
- 7) All RSE's were measured with 1CC. It was determined that adding more CC's causes the overall amplitude of just 1CC to decrease, therefore, 1CC is the worst case for the purposes of spurious emissions measurements.
- 8) The "-" shown in the following RSE tables are used to denote a noise floor measurement.
- 9) All RSE's were investigated in EN-DC mode and with 802.11 chipset active. It was determined that there is no new emission introduced by EN-DC mode, or the 802.11 chipset. For EN-DC mode, the anchor bands are: LTE B13, B5, B4, B66 and B2.
- 10) For the n261 band spurious emission measurements, the spectrum directly below the fundamental frequency is investigated from 18 - 27.375GHz and the spectrum directly above the fundamental frequency is investigated from 28.475 - 40GHz. The portion of spectrum from 27.375 – 27.5GHz and 28.35 - 28.475GHz is shown Section 7.5 which covers band edge emissions.
- 11) For the n260 band spurious emission measurements, the spectrum directly below the fundamental frequency is investigated from 18 - 36.85GHz and the spectrum directly above the fundamental frequency is investigated from 40.15 - 60GHz. The portion of spectrum from 36.85 - 40GHz and 40 - 40.15GHz is shown Section 7.5 which covers band edge emissions.
- 12) Both bands were investigated and the worst case antenna with the MIMO measurements for Radiated Spurious Emissions are reported.

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Band n261 – Ant3 30MHz - 1GHz



Plot 7-9. Ant3-n261 Radiated Spurious Plot (1CC DFT-s-OFDM-BPSK Mid Channel H Beam)



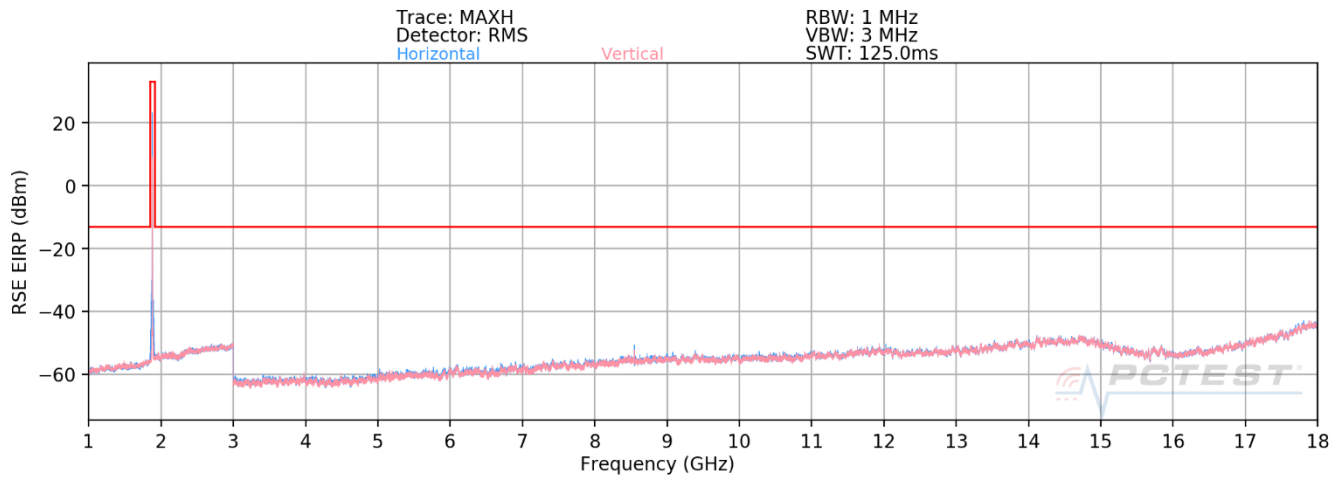
Plot 7-10. Ant3-n261 Radiated Spurious Plot (1CC DFT-s-OFDM-BPSK Mid Channel V Beam)

Note:

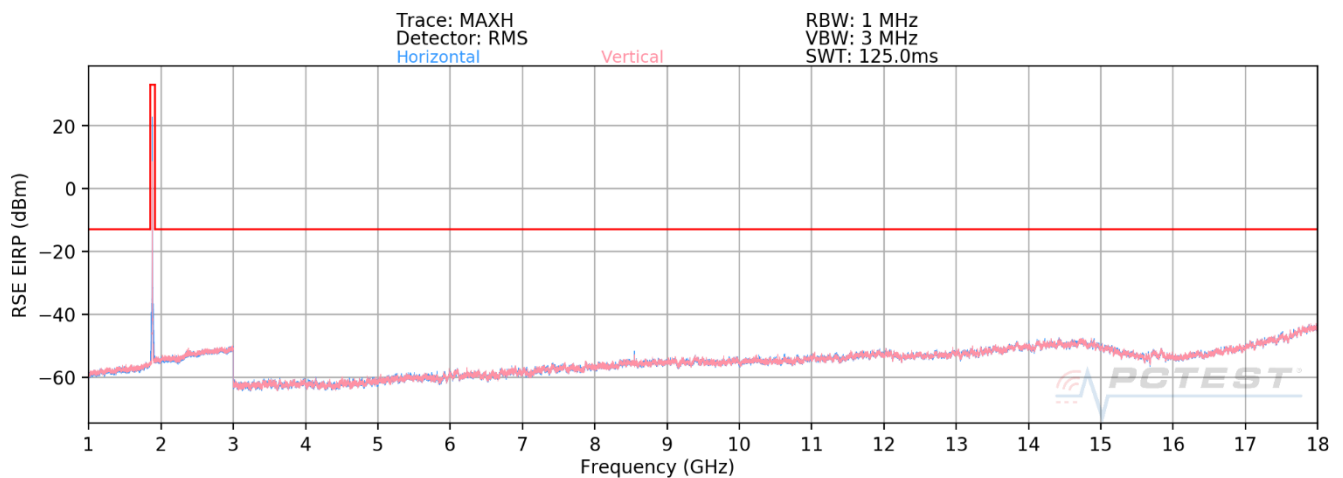
The emissions observed in pre-scans were investigated in detail and are not failing. The RSEs were found to have more than 60dB margin from the limit.

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1GHz - 18GHz



Plot 7-11. Ant3-n261 Radiated Spurious Plot 1GHz - 18GHz (1CC DFT-s-OFDM-BPSK Mid Channel H Beam – ENDC Anchor Band 2)



Plot 7-12. Ant3-n261 Radiated Spurious Plot 1GHz - 18GHz (1CC DFT-s-OFDM-BPSK Mid Channel V Beam - – ENDC Anchor Band 2)

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Spurious Emissions EIRP Sample Calculation (n261)

The raw radiated spurious level is converted to field strength in dBuV/m. Then, the RSE EIRP level is calculated by applying the additional factors shown below for a test distance of 1 meter.

$$\text{RSE EIRP (dBm)} = \text{Analyzer Level (dBm)} + 107 + \text{AFCL (dB/m)} + 20\text{Log(Dm)} - 104.8$$

Channel	Bandwidth (MHz)	Modulation	Spurious Emission Level [dBm]	Limit [dBm]	Margin [dB]
Low	50	BPSK	-49.29	-13.00	-36.29
Mid	50	BPSK	-47.46	-13.00	-34.46
High	50	BPSK	-51.66	-13.00	-38.66

Table 7-9. Ant3 - MIMO -Spurious Emissions Table (1GHz - 18GHz)

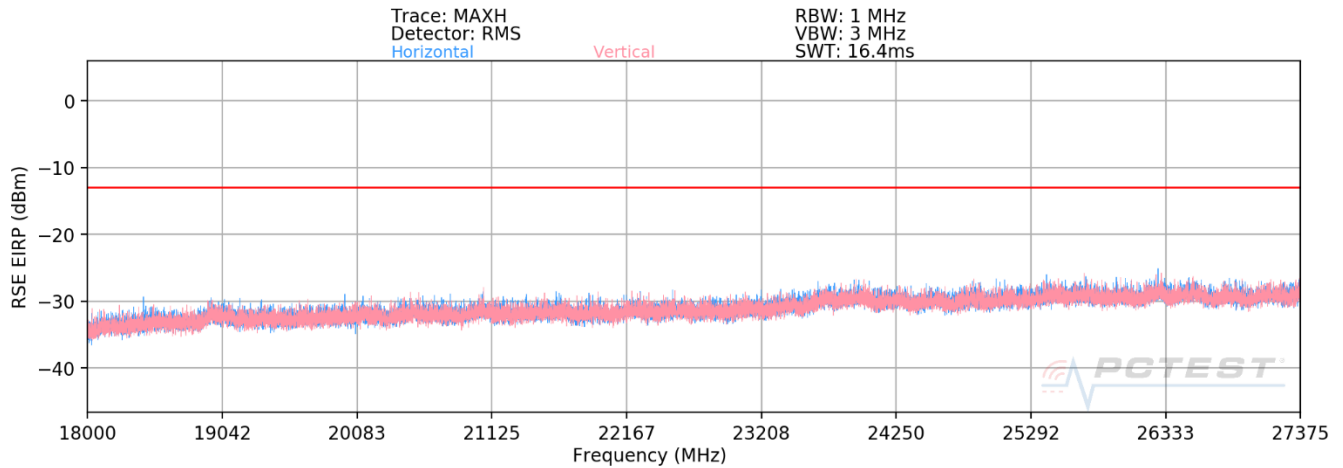
Notes

1. The RSE EIRP level is taken directly from the spectrum analyzer which includes the appropriate antenna factors, cable losses, and harmonic mixer conversion losses. Measurements were performed at a distance of 1 meter.
2. To address compliance of MIMO RSE per KDB 662911 D01, the MIMO RSE EIRP is calculated by summing the worst case H Beam EIRP and V Beam EIRP in linear powers units then converted back to dBm:

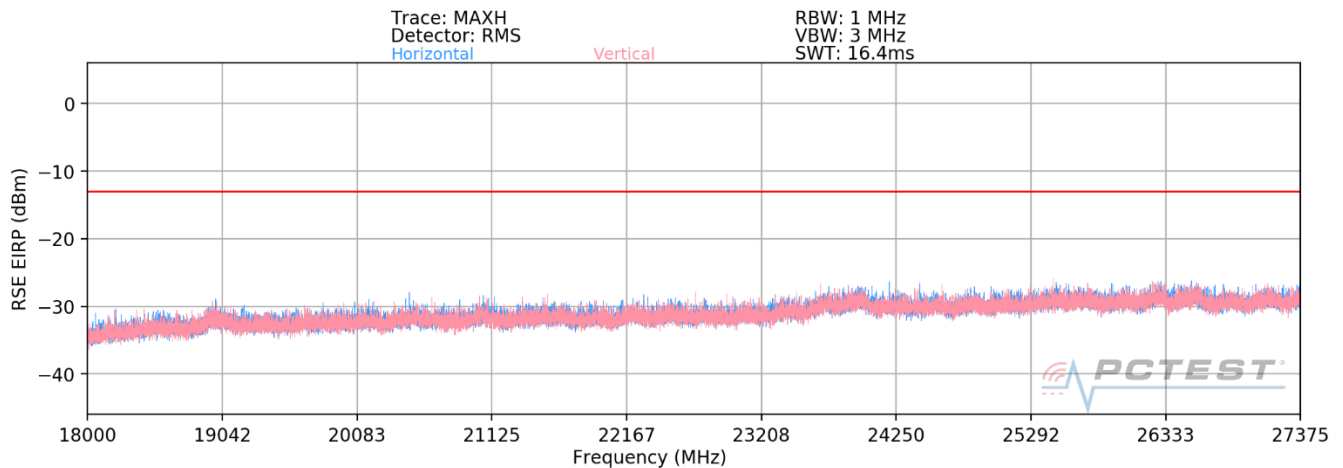
$$\text{EIRP(H Beam)} + \text{EIRP(V Beam)} = \text{EIRP(MIMO)}$$

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18GHz - 27.375GHz



Plot 7-13. Ant3-n261 Radiated Spurious Plot (1CC DFT-s-OFDM-BPSK Mid Channel H Beam – ENDC Anchor B2)



Plot 7-14. Ant3-n261 Radiated Spurious Plot (1CC DFT-s-OFDM-BPSK Mid Channel V Beam – ENDC Anchor B2)

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Spurious Emissions EIRP Sample Calculation (n261)

The raw radiated spurious level is converted to field strength in dBuV/m. Then, the RSE EIRP level is calculated by applying the additional factors shown below for a test distance of 1 meter.

$$\text{RSE EIRP (dBm)} = \text{Analyzer Level (dBm)} + 107 + \text{AFCL (dB/m)} + 20\text{Log(Dm)} - 104.8$$

Channel	Bandwidth (MHz)	Modulation	Spurious Emission Level [dBm]	Limit [dBm]	Margin [dB]
Low	50	BPSK	-22.87	-13.00	-9.87
Mid	50	BPSK	-30.06	-13.00	-17.06
High	50	BPSK	-31.50	-13.00	-18.50

Table 7-10. Ant3 - MIMO -Spurious Emissions Table (18GHz - 27.375GHz)

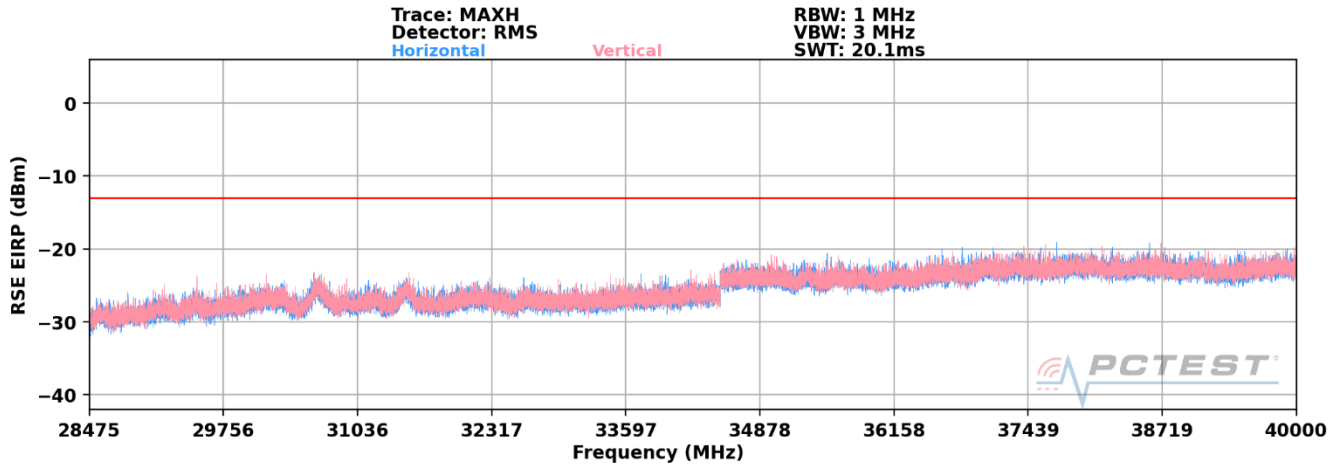
Notes

1. The RSE EIRP level is taken directly from the spectrum analyzer which includes the appropriate antenna factors, cable losses, and harmonic mixer conversion losses. Measurements were performed at a distance of 1 meter.
2. To address compliance of MIMO RSE per KDB 662911 D01, the MIMO RSE EIRP is calculated by summing the worst case H Beam EIRP and V Beam EIRP in linear powers units then converted back to dBm:

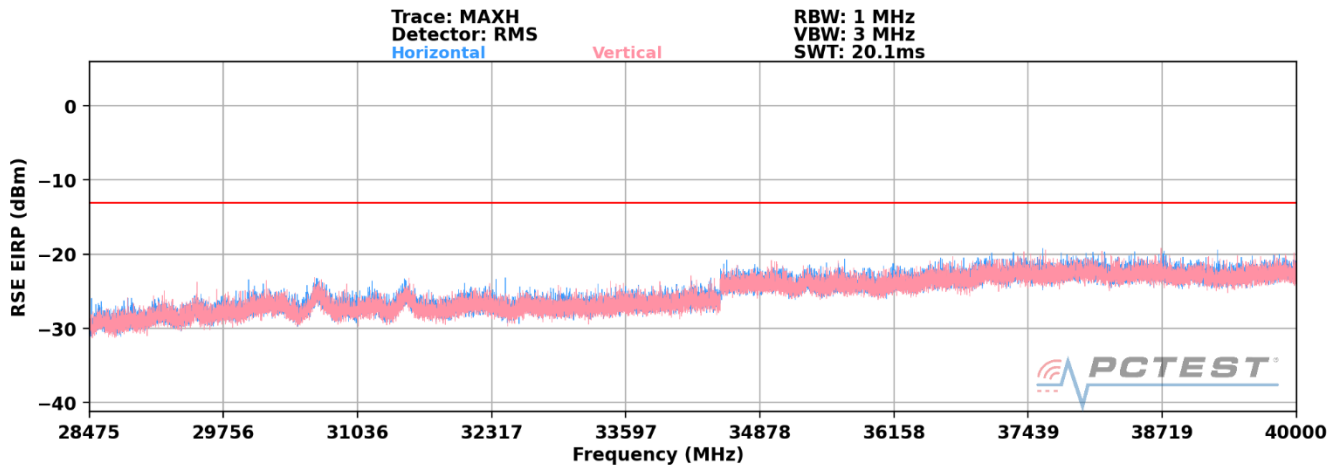
$$\text{EIRP(H Beam)} + \text{EIRP(V Beam)} = \text{EIRP(MIMO)}$$

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28.475GHz - 40GHz



Plot 7-15. Ant3-n261 Radiated Spurious Plot (1CC DFT-s-OFDM-BPSK Mid Channel H Beam – ENDC Anchor B2)



Plot 7-16. Ant3-n261 Radiated Spurious Plot (1CC DFT-s-OFDM-BPSK Mid Channel V Beam – ENDC Anchor B2)

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Spurious Emissions EIRP Sample Calculation (n261)

The raw radiated spurious level is converted to field strength in dBuV/m. Then, the RSE EIRP level is calculated by applying the additional factors shown below for a test distance of 1 meter.

$$\text{RSE EIRP (dBm)} = \text{Analyzer Level (dBm)} + 107 + \text{AFCL (dB/m)} + 20\text{Log(Dm)} - 104.8$$

Channel	Bandwidth (MHz)	Modulation	Spurious Emission Level [dBm]	Limit [dBm]	Margin [dB]
Low	50	BPSK	-19.81	-13.00	-6.81
Mid	50	BPSK	-25.10	-13.00	-12.10
High	50	BPSK	-23.78	-13.00	-10.78

Table 7-11. Ant3 - MIMO -Spurious Emissions Table (28.475GHz - 40GHz)

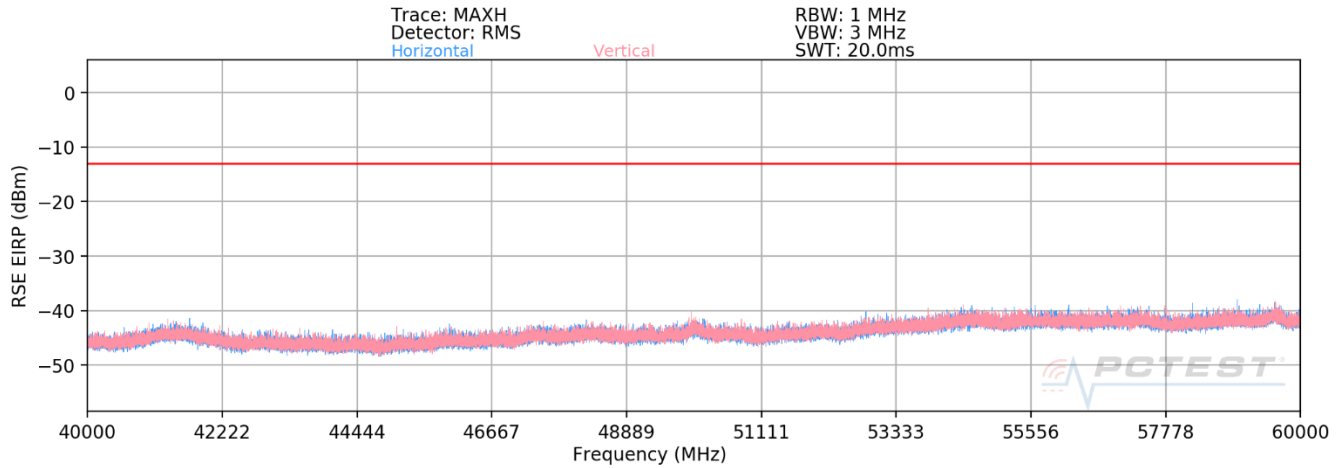
Notes

1. The RSE EIRP level is taken directly from the spectrum analyzer which includes the appropriate antenna factors, cable losses, and harmonic mixer conversion losses. Measurements were performed at a distance of 1 meter.
2. To address compliance of MIMO RSE per KDB 662911 D01, the MIMO RSE EIRP is calculated by summing the worst case H Beam EIRP and V Beam EIRP in linear powers units then converted back to dBm:

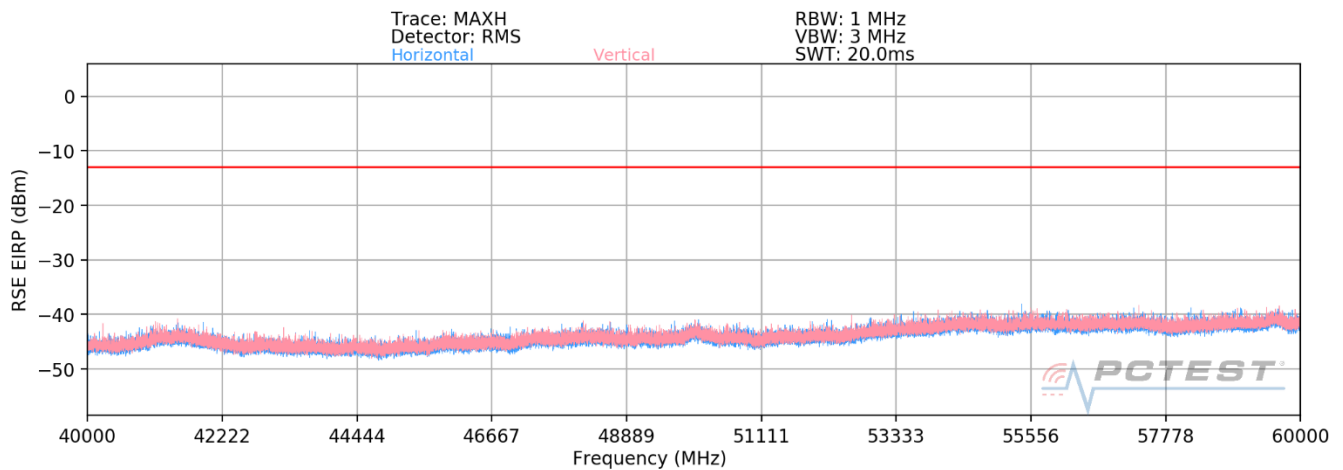
$$\text{EIRP(H Beam)} + \text{EIRP(V Beam)} = \text{EIRP(MIMO)}$$

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40GHz - 60GHz



Plot 7-17. Ant3-n261 Radiated Spurious Plot (1CC DFT-s-OFDM-BPSK Mid Channel H Beam – ENDC Anchor B2)



Plot 7-18. Ant3-n261 Radiated Spurious Plot (1CC DFT-s-OFDM-BPSK Mid Channel V Beam – ENDC Anchor B2)

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Spurious Emissions EIRP Sample Calculation (n261)

The raw radiated spurious level is converted to field strength in dBuV/m. Then, the RSE EIRP level is calculated by applying the additional factors shown below for a test distance of 1.5 meter.

RSE EIRP (dBm) = Analyzer Level (dBm) + 107 + AFCL (dB/m) + 20Log(Dm) – 104.8 + Harmonic Mixer Conversion Loss [dB]

Channel	Bandwidth (MHz)	Modulation	Spurious Emission Level [dBm]	Limit [dBm]	Margin [dB]
Low	50	BPSK	-38.95	-13.00	-25.95
Mid	50	BPSK	-39.94	-13.00	-26.94
High	50	BPSK	-39.91	-13.00	-26.91

Table 7-12. Ant3 - MIMO -Spurious Emissions Table (40GHz - 60GHz)

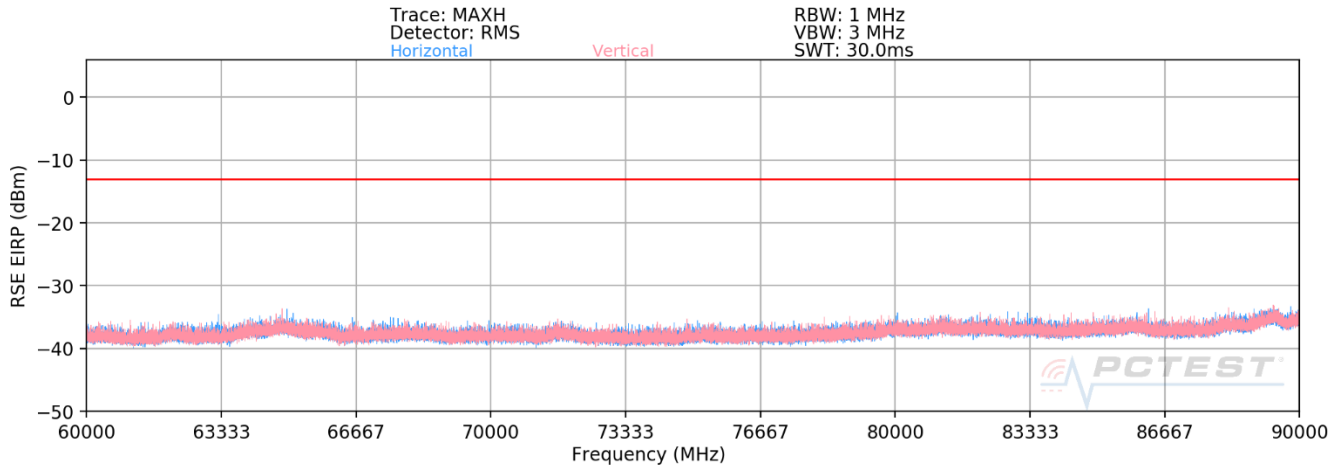
Notes

1. The RSE EIRP level is taken directly from the spectrum analyzer which includes the appropriate antenna factors, cable losses, and harmonic mixer conversion losses. Measurements were performed at a distance of 1 meter.
2. To address compliance of MIMO RSE per KDB 662911 D01, the MIMO RSE EIRP is calculated by summing the worst case H Beam EIRP and V Beam EIRP in linear powers units then converted back to dBm:

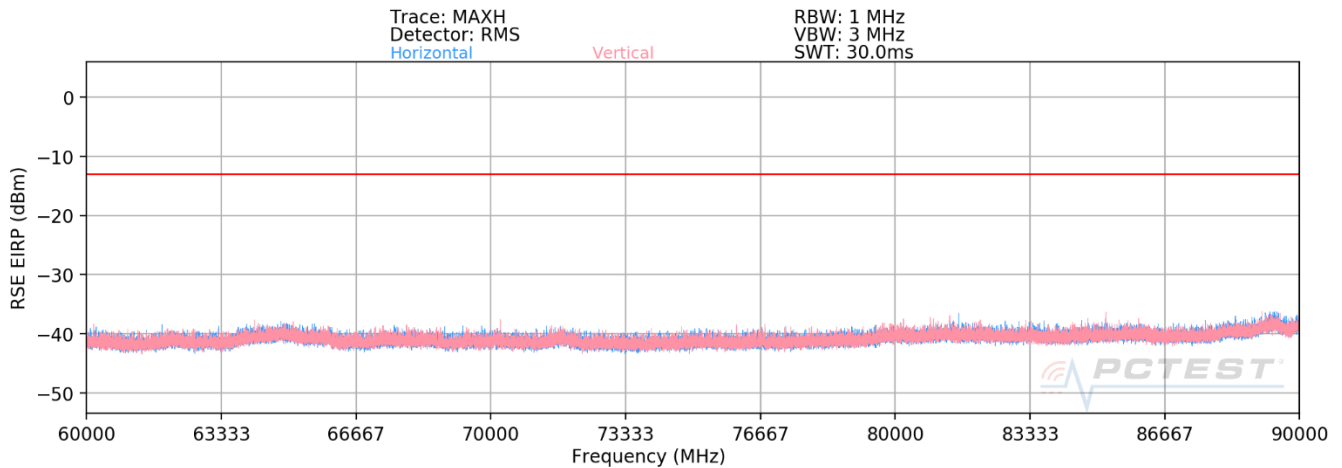
$$\text{EIRP(H Beam)} + \text{EIRP(V Beam)} = \text{EIRP(MIMO)}$$

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60GHz - 90GHz



Plot 7-19. Ant3-n261 Radiated Spurious Plot (1CC DFT-s-OFDM-BPSK Mid Channel H Beam – ENDC Anchor B2)



Plot 7-20. Ant3-n261 Radiated Spurious Plot (1CC DFT-s-OFDM-BPSK Mid Channel V Beam – ENDC Anchor B2)

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7.5 Band Edge Emissions

\$2.1051, \$30.203

Test Overview

All out of band emissions are measured in a radiated setup while the EUT is operating at its maximum duty cycle, at maximum power, and at the appropriate frequencies. All modulations were investigated to determine the worst case configuration. All modes of operation were investigated and the worst case configuration results are reported in this section.

The minimum permissible attenuation level of any spurious emission is -13dBm/1MHz. However, in the bands immediately outside and adjacent to the licensee's frequency block, having a bandwidth equal to 10 percent of the channel bandwidth, the conductive power or the total radiated power of any emission shall be -5 dBm/MHz or lower.

Test Procedure Used

ANSI C63.26-2015 Section 5 and ANSI C63.26-2015 Section 6.4
KDB 842590 D01 v01 Section 4.4.2.5

Test Settings

1. Start and stop frequency were set such that both upper and lower band edges are measured.
2. Span was set large enough so as to capture all out of band emissions near the band edge
3. RBW = 1MHz
4. VBW $\geq 3 \times$ RBW
5. Detector = RMS
6. Number of sweep points $\geq 2 \times$ Span/RBW
7. Trace mode = trace average
8. Sweep time = auto couple
9. The trace was allowed to stabilize

Test Notes

- 1) The EUT was tested in three orthogonal planes and in all possible test configurations and positioning.
- 2) Band Edge measurements in this section are shown as equivalent conductive powers for direct comparison to the 30.203 limit. The conductive power at the band edge is calculated by subtracting the gain of the EUT's antenna from the measured EIRP level. Antenna Gain information is shown on the following page.
- 3) Band Edge emissions were measured at a 1 meter distance.
- 4) The spectrum analyzer for each measurement shows an offset value that was determined using the measurement antenna factor, cable loss, far field measurement distance, and EUT antenna gain. A sample calculation is shown on the following page.
- 5) The antenna gains applied to the measurements in the plots shown in this section are accurate for the displayed spectrum.
- 6) MIMO Band Edge plots shown below are mathematically summed conductive powers between spectrum analyzer measurements on H Beam and V Beam. This MIMO bandedge plot was produced by summing the following two spectrum analyzer traces: (1) the first trace is maximized while the EUT is transmitting in H-beam and (2) the second trace is maximized while the EUT is transmitting in V-beam.
- 7) The MIMO Band Edges were calculated by using the "measure and sum the spectra across the outputs" technique specified in Section 6.4.3.2.2 of ANSI C63.26-2015. The spectra were summed linearly and converted to dBm for comparison with the limit.

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Antenna Gain Information at the Band Edge

The following antenna gain information is provided to demonstrate the antenna performance of the 27.5 – 28.35GHz and 37 – 40GHz band. These antenna gains were subtracted from the measured EIRP levels at the lower and upper band edge frequencies to determine an equivalent conductive power that was compared directly with the §30.203 limits.

Antenna	Channel	Beam Polarization	Gain (dBi)
Ant4	Low	H	8.77
		V	7.73
	High	H	9.12
		V	8.05

Table 7-13. Antenna Gains at the Band Edges(n261)

Antenna	Channel	Beam Polarization	Gain (dBi)
Ant3	Low	H	9.95
		V	10.25
	High	H	9.64
		V	10.36

Table 7-14. Antenna Gains at the Band Edges(n260)

Sample Analyzer Offset Calculation (at 27.5GHz)

Measurement Antenna Factor = 40.70dB/m

Cable Loss = 8.82dB

EUT Antenna Gain = 6.60dBi

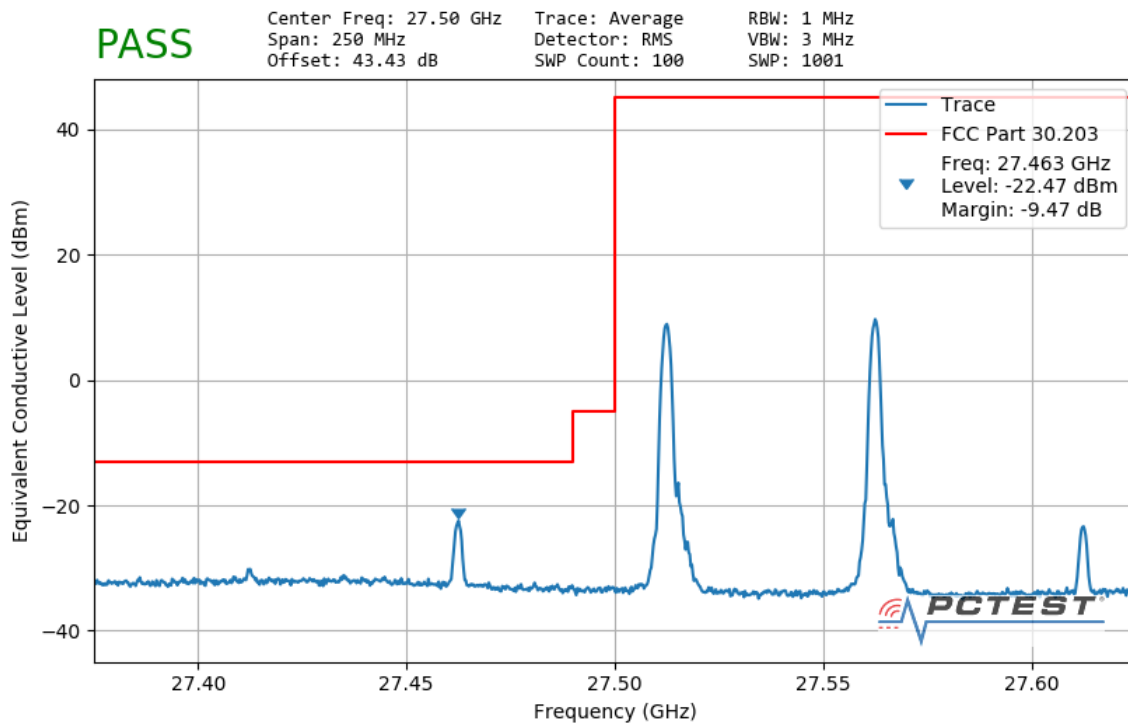
Analyzer Offset (dB) = AF (dB/m) + CL (dB) + 107 + 20log₁₀(D) – 104.8dB – Gain (dBi), where D = 1m

$$= 40.70\text{dB/m} + 8.82\text{dB} + 107 + 20\log_{10}(1\text{m}) - 104.8\text{dB} - 6.60\text{dBi}$$

$$= 45.12\text{dB}$$

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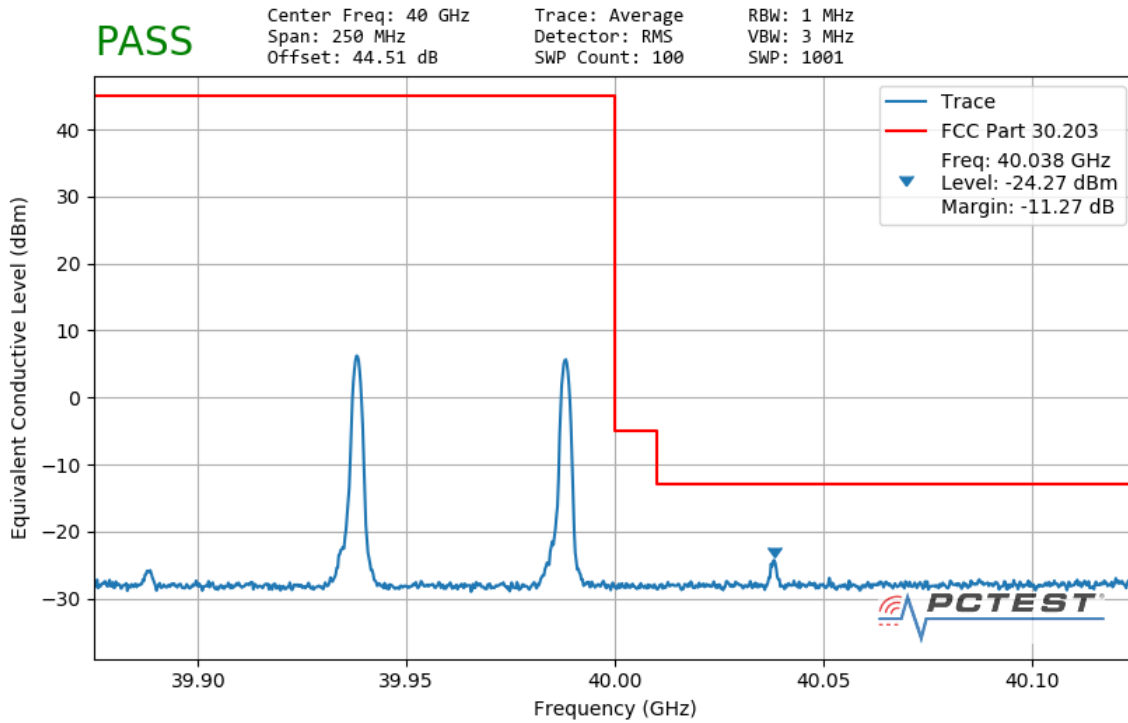
Band n261 - MIMO



Plot 7-21. Ant4 Lower Band Edge (50MHz-2CC – BPSK 1 RB)

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Band n260 - MIMO



Plot 7-22. Ant3 Upper Band Edge (50MHz-2CC – BPSK 1 RB)

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8.0 CONCLUSION

The data collected relate only to the item(s) tested and show that the **Samsung Portable Handset FCC ID: A3LSMG988U** complies with all the requirements of Part 30.

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9.0 APPENDIX A

9.1 VDI Mixer Verification Certificate



Virginia Diodes, Inc

979 2nd St. SE
Suite 309
Charlottesville, VA 22902
Phone: 434-297-3257
Fax: 434-297-3258

Certificate of Conformance

To: PCTEST Engineering Laboratory
6660-B Dobbin Road
Columbia, MD 21045
United States

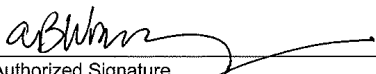
From: Virginia Diodes, Inc
979 2nd St. SE
Suite 309
Charlottesville, VA 22902

Shipping Date: 05/14/18

Today's Date: 05/14/18

Quantity		
<u>Shipped</u>	<u>Unit</u>	<u>Description</u>
1	EA	VDIWR12.0SAX WR12SAX - Spectrum Analyzer Extension Module / SN: SAX 252

The VDI product(s) in this shipment meet(s) the guidelines for performance specifications established in accordance with the corresponding Purchase Order. Data presented in the User Guide, where applicable, has been obtained in accordance with VDI's Quality Management System. All instruments, used to obtain data, which require calibration have been calibrated with equipment traceable to the National Institute of Standards and Technology (NIST) and through NIST to the International System of Units (SI).


Authorized Signature
Virginia Diodes, Inc

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United States

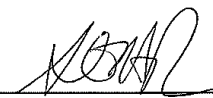
From: Virginia Diodes, Inc
979 2nd St. SE
Suite 309
Charlottesville, VA 22902

Shipping Date: 05/08/18

Today's Date: 05/08/18

Quantity	Shipped	Unit	Description
1	EA	VDIWR8.0SAX	WR8.0SAX - Spectrum Analyzer Extension Module; SN: SAX 253.

The VDI product(s) in this shipment meet(s) the guidelines for performance specifications established in accordance with the corresponding Purchase Order. Data presented in the User Guide, where applicable, has been obtained in accordance with VDI's Quality Management System. All instruments, used to obtain data, which require calibration have been calibrated with equipment traceable to the National Institute of Standards and Technology (NIST) and through NIST to the International System of Units (SI).


Authorized Signature
Virginia Diodes, Inc

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Phone: 434-297-3257
Fax: 434-297-3258

Certificate of Conformance

To: PCTEST Engineering Laboratory
6660-B Dobbin Road
Columbia, MD 21045
United States

From: Virginia Diodes, Inc
979 2nd St. SE
Suite 309
Charlottesville, VA 22902

Shipping Date: 05/21/18	Today's Date: 05/22/18
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Quantity	Shipped	Unit	Description
	1	EA	VDIWR5.1SAX WR5.1SAX - Spectrum Analyzer Extension Module; SN: SAX 254.

The VDI product(s) in this shipment meet(s) the guidelines for performance specifications established in accordance with the corresponding Purchase Order. Data presented in the User Guide, where applicable, has been obtained in accordance with VDI's Quality Management System. All instruments, used to obtain data, which require calibration have been calibrated with equipment traceable to the National Institute of Standards and Technology (NIST) and through NIST to the International System of Units (SI).


Authorized Signature
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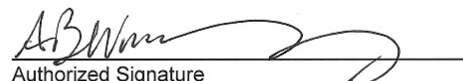
From: Virginia Diodes, Inc
979 2nd St. SE
Suite 309
Charlottesville, VA 22902

Packing List No: 193065

Today's Date: 10/02/19

Quantity	Shipped	Unit	Description	Order-Job Number
1		EA	VDIWR19.0SAX WR19SAX / SN: SAX 411	19329-01

The VDI product(s) in this shipment meet(s) the guidelines for performance specifications established in accordance with the corresponding Purchase Order. Data presented in the User Guide, where applicable, has been obtained in accordance with VDI's Quality Management System. All instruments, used to obtain data, which require calibration have been calibrated with equipment traceable to the National Institute of Standards and Technology (NIST) and through NIST to the International System of Units (SI).


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Virginia Diodes, Inc

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